

AMAT-SemVision CX Defect Review System

Tool

Manufacturer: AMAT

Model: CX

Wafer Size: 300mm

Technical specifications

Illumination mode: E-Beam

4nm resolution at 1kV

Thermo Noran EDX spectrometer

Automatic defect review and classification capability

Supports 8" and 12" wafers

Multi perspective imaging (3 perspectives)

EDX and Imaging accelerating voltage from 500V to 15kV

SEM AutoFocus

Sony 990 CCD

Optical video Image 2.5x, 20x and 100x

Equipment

Vacuum chamber

Three Wafer tilt positions. 0, 15 and 45 degrees

SGI hard drive size: 72GB

Roughing pump stack: Edwards IDQP40 and IDQP80 (subject to availability)

Fully SECS 2 compatible

Two Brooks automation fixed load load ports

EDX capability requires cryogenic compressor (subject to availability)

Operator Interface

SGI (main computer) uses IRIX by silicon graphics

EDX uses Sun Sparc5 Solaris Operating system

MEC (for E-Beam gun) uses Windows NT

WHC (Wafer handling) uses Windows NT

Image Computer uses Windows NT

Supports NFS (network file sharing)

Application Software 5.0.430 compatible